

Notice of References Cited		Application/Control No. 10/530,084	Applicant(s)/Patent Under Reexamination HAENEN ET AL.	
		Examiner SATHAVARAM I. REDDY	Art Unit 1794	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,460,637	07-1984	Miyamoto et al.	428/32.32
*	B	US-5,437,913	08-1995	Asaka et al.	428/195.1
*	C	US-5,418,078	05-1995	Desie et al.	428/32.3
*	D	US-4,408,010	10-1983	Le-Khac, Bi	525/73
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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